

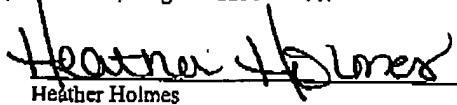
PATENT

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H1906/AMDP985US

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence (along with any paper referred to as being attached or enclosed) is being faxed to 703-872-9306 on the date shown below to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450.

Date: 11/22/04


Heather Holmes
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:

Applicant(s): Khoi A. Phan, *et al.*

Examiner: Phuc T. Dang

Serial No: 10/653,309

Art Unit: 2818

Filing Date: September 2, 2003

Title: PATTERN RECOGNITION AND METROLOGY STRUCTURE FOR AN X-INITIATIVE LAYOUT DESIGN

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

**REPLY TO RESTRICTION REQUIREMENT DATED OCTOBER 12, 2004 AND
 PRELIMINARY AMENDMENT**

Dear Sir:

This Reply is in response to the Restriction Requirement mailed on October 12, 2004 in connection with the above-identified patent application.

The Examiner requires restriction to one of the following two groups of claims:

Group I – Claims 1-13, 20, 23 and 25, drawn to a system and a process of ~~aligning a wafer to a reticle~~ 10/653,309 for aligning a wafer to a reticle, classified in class 257, subclass 98.

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Group II – Claims 14-19, 21-22 and 24, drawn to a system and a process of using for facilitating surface inspection utilizing surface inspection equipment, classified in class 438, subclass 462.

Applicants' representative hereby elects with traverse Group I (claims 1-13, 20, 23 and 25) for further prosecution on the merits.